

# George Papaioannou

## List of Publications by Year in descending order

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Version: 2024-02-01

26  
papers

306  
citations

933447

10  
h-index

888059

17  
g-index

26  
all docs

26  
docs citations

26  
times ranked

324  
citing authors

#	ARTICLE	IF	CITATIONS
1	On the reliability of electrostatic NEMS/MEMS devices: Review of present knowledge on the dielectric charging and stiction failure mechanisms and novel characterization methodologies. <i>Microelectronics Reliability</i> , 2011, 51, 1810-1818.	1.7	54
2	Effect of deposition conditions on charging processes in SiNx: Application to RF-MEMS capacitive switches. <i>Microelectronic Engineering</i> , 2009, 86, 404-407.	2.4	45
3	Low Work Function Lacunary Polyoxometalates as Electron Transport Interlayers for Inverted Polymer Solar Cells of Improved Efficiency and Stability. <i>ACS Applied Materials &amp; Interfaces</i> , 2017, 9, 22773-22787.	8.0	23
4	Investigation of silicon nitride charging. <i>Microelectronic Engineering</i> , 2012, 90, 145-148.	2.4	22
5	Engineering of Porphyrin Molecules for Use as Effective Cathode Interfacial Modifiers in Organic Solar Cells of Enhanced Efficiency and Stability. <i>ACS Applied Materials &amp; Interfaces</i> , 2018, 10, 20728-20739.	8.0	22
6	Low-temperature properties and phototransport in silicon-on-insulator films synthesized by oxygen implantation. <i>Journal of Applied Physics</i> , 1988, 63, 4575-4579.	2.5	17
7	Charge collection mechanism in MEMS capacitive switches. , 2012, , .		13
8	A correlation of capacitive RF-MEMS reliability to AlN dielectric film spontaneous polarization. <i>International Journal of Microwave and Wireless Technologies</i> , 2009, 1, 43-47.	1.9	12
9	Physics of Charging in Dielectrics and Reliability of Capacitive RF-MEMS Switches. , 0, , .		11
10	Nanotribology-based novel characterization techniques for the dielectric charging failure mechanism in electrostatically actuated NEMS/MEMS devices using force-distance curve measurements. <i>Journal of Colloid and Interface Science</i> , 2012, 365, 236-253.	9.4	11
11	Functionalized Zinc Porphyrins with Various Peripheral Groups for Interfacial Electron Injection Barrier Control in Organic Light Emitting Diodes. <i>ACS Omega</i> , 2018, 3, 10008-10018.	3.5	11
12	Optimization of Dielectric Material Stoichiometry for High-Reliability Capacitive MEMS Switches. <i>IEEE Microwave and Wireless Components Letters</i> , 2016, 26, 174-176.	3.2	10
13	On the Discharge Transport Mechanisms Through the Dielectric Film in MEMS Capacitive Switches. <i>Journal of Microelectromechanical Systems</i> , 2020, 29, 202-213.	2.5	10
14	Dielectric Discharging processes in RF-MEMS Capacitive Switches. , 2007, , .		9
15	The Impact of Dielectric Material and Temperature on Dielectric Charging in RF MEMS Capacitive Switches. <i>NATO Science for Peace and Security Series B: Physics and Biophysics</i> , 2010, , 141-153.	0.3	8
16	Dielectric Charging Asymmetry in SiN Films Used in RF MEMS Capacitive Switches. <i>IEEE Transactions on Device and Materials Reliability</i> , 2017, 17, 138-145.	2.0	8
17	A MIM capacitor study of dielectric charging for RF MEMS capacitive switches. <i>Facta Universitatis - Series Electronics and Energetics</i> , 2015, 28, 113-122.	0.9	5
18	Dependence of dielectric charging on film thickness and deposition conditions. , 2008, , .		4

#	ARTICLE	IF	CITATIONS
19	Dielectric Charging in Capacitive RF MEMS Switches: The Effect of Extended Durations of Electric Stress. IEEE Microwave and Wireless Components Letters, 2011, 21, 592-594.	3.2	4
20	Bandpass filter modeling employing Lorentzian distribution. Microwave and Optical Technology Letters, 2009, 51, 1167-1169.	1.4	2
21	Reliability assessment of electrostatically driven MEMS devices: based on a pulse-induced charging technique. Journal of Micromechanics and Microengineering, 2012, 22, 045016.	2.6	2
22	RF-MEMS Dielectric Charging: Dependence on Dielectric Film Polarization Procedures. , 2007, , .		1
23	Modelling of the dynamical behaviour of floating electrode MEMS. , 2015, , .		1
24	Effect of Ambient on the Field Emission Induced-Damage in Dielectric-Less MEMS Capacitive Structures. IEEE Transactions on Device and Materials Reliability, 2022, 22, 205-216.	2.0	1
25	A simple constitutive model for dielectric charging based on Frenkel-Poole mechanism. , 2015, , .		0
26	Conductive reliability modelling of capacitive MEMS. , 2015, , .		0